

<b>Notice of References Cited</b>	Application/Control No. 10/556,355		Applicant(s)/Patent Under Reexamination IIZUKA, HACHISHIRO	
	Examiner KEATH T. CHEN		Art Unit 1792	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0000379	01-2004	Slyke et al.	159/22
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#### FOREIGN PATENT DOCUMENTS

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